

ADG506A/ADG507A

FEATURES

- 44 V Supply Maximum Rating
- V_{SS} to V_{DD} Analog Signal Range
- Single/Dual Supply Specifications
- Wide Supply Ranges (10.8 V to 16.5 V)
- Extended Plastic Temperature Range
(-40°C to $+85^{\circ}\text{C}$)
- Low Power Dissipation (28 mW max)
- Low Leakage (20 pA typ)
- Available in 28-Lead DIP, SOIC, PLCC, TSSOP and LCCC Packages
- Superior Alternative to:
DG506A, HI-506
DG507A, HI-507

FUNCTIONAL BLOCK DIAGRAM



GENERAL DESCRIPTION

The ADG506A and ADG507A are CMOS monolithic analog multiplexers with 16 channels and dual 8 channels, respectively. The ADG506A switches one of 16 inputs to a common output, depending on the state of four binary addresses and an enable input. The ADG507A switches one of eight differential inputs to a common differential output, depending on the state of three binary addresses and an enable input. Both devices have TTL and 5 V CMOS logic compatible digital inputs.

The ADG506A and ADG507A are designed on an enhanced LC^2MOS process, which gives an increased signal capability of V_{SS} to V_{DD} and enables operation over a wide range of supply voltages. The devices can operate comfortably anywhere in the 10.8 V to 16.5 V single or dual supply range. These multiplexers also feature high switching speeds and low R_{ON} .

PRODUCT HIGHLIGHTS

1. Single/Dual Supply Specifications with a Wide Tolerance
The devices are specified in the 10.8 V to 16.5 V range for both single and dual supplies.
2. Extended Signal Range
The enhanced LC^2MOS processing results in a high breakdown and an increased analog signal range of V_{SS} to V_{DD} .
3. Break-Before-Make Switching
Switches are guaranteed break-before-make so input signals are protected against momentary shorting.
4. Low Leakage
Leakage currents in the range of 20 pA make these multiplexers suitable for high precision circuits.

ORDERING GUIDE

| Model ¹ | Temperature Range | Package Option ² |
|--------------------|---|-----------------------------|
| ADG506AKN | -40°C to $+85^{\circ}\text{C}$ | N-28 |
| ADG506AKR | -40°C to $+85^{\circ}\text{C}$ | R-28 |
| ADG506AKP | -40°C to $+85^{\circ}\text{C}$ | P-28A |
| ADG506ABQ | -40°C to $+85^{\circ}\text{C}$ | Q-28 |
| ADG506ATQ | -55°C to $+125^{\circ}\text{C}$ | Q-28 |
| ADG506ATE | -55°C to $+125^{\circ}\text{C}$ | E-28A |
| ADG507AKN | -40°C to $+85^{\circ}\text{C}$ | N-28 |
| ADG507AKR | -40°C to $+85^{\circ}\text{C}$ | R-28 |
| ADG507AKP | -40°C to $+85^{\circ}\text{C}$ | P-28A |
| ADG507AKRU | -40°C to $+85^{\circ}\text{C}$ | RU-28 |
| ADG507ABQ | -40°C to $+85^{\circ}\text{C}$ | Q-28 |
| ADG507ATQ | -55°C to $+125^{\circ}\text{C}$ | Q-28 |
| ADG507ATE | -55°C to $+125^{\circ}\text{C}$ | E-28A |

NOTES

¹To order MIL-STD-883, Class B processed parts, add /883B to part number. See Analog Devices' *Military/Aerospace Reference Manual* (1994) for military data sheet.

²E = Leadless Ceramic Chip Carrier (LCCC); N = Plastic DIP; P = Plastic Leaded Chip Carrier (PLCC); Q = Cerdip; R = 0.3" Small Outline IC (SOIC); RU = Thin Shrink Small Outline Package (TSSOP).

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ADG506A/ADG507A—SPECIFICATIONS

Dual Supply ($V_{DD} = +10.8\text{ V to }+16.5\text{ V}$, $V_{SS} = -10.8\text{ V to }-16.5\text{ V}$ unless otherwise noted)

| Parameter | ADG506A ADG507A K Version | | ADG506A ADG507A B Version | | ADG506A ADG507A T Version | | Units | Comments |
|---|---------------------------------|-------------------|---------------------------------|-------------------|---------------------------------|--------------------|---------------------------|---|
| | +25°C | -40°C to +85°C | +25°C | -40°C to +85°C | +25°C | -55°C to +125°C | | |
| ANALOG SWITCH | | | | | | | | |
| Analog Signal Range | V_{SS} | V_{SS} | V_{SS} | V_{SS} | V_{SS} | V_{SS} | V min | |
| | V_{DD} | V_{DD} | V_{DD} | V_{DD} | V_{DD} | V_{DD} | V max | |
| R_{ON} | 280 | | 280 | | 280 | | Ω typ | $-10\text{ V} \leq V_S \leq +10\text{ V}$, $I_{DS} = 1\text{ mA}$; Test Circuit 1 |
| | 450 | 600 | 450 | 600 | 450 | 600 | Ω max | |
| | 300 | 400 | 300 | 400 | | | Ω max | $V_{DD} = 15\text{ V} (\pm 10\%)$, $V_{SS} = -15\text{ V} (\pm 10\%)$ |
| R_{ON} Drift | 0.6 | | 0.6 | | 0.6 | 400 | $\%/^{\circ}\text{C}$ typ | $V_{DD} = 15\text{ V} (\pm 5\%)$, $V_{SS} = -15\text{ V} (\pm 5\%)$ |
| R_{ON} Match | 5 | | 5 | | 5 | | % typ | $-10\text{ V} \leq V_S \leq +10\text{ V}$, $I_{DS} = 1\text{ mA}$ |
| | | | | | | | | $-10\text{ V} \leq V_S \leq +10\text{ V}$, $I_{DS} = 1\text{ mA}$ |
| I_S (OFF), Off Input Leakage | 0.02 | | 0.02 | | 0.02 | | nA typ | $V_1 = \pm 10\text{ V}$, $V_2 = \mp 10\text{ V}$; Test Circuit 2 |
| | 1 | 50 | 1 | 50 | 1 | 50 | nA max | |
| I_D (OFF), Off Output Leakage | 0.04 | | 0.04 | | 0.04 | | nA typ | $V_1 = \pm 10\text{ V}$, $V_2 = \mp 10\text{ V}$; Test Circuit 3 |
| ADG506A | 1 | 200 | 1 | 200 | 1 | 200 | nA max | |
| ADG507A | 1 | 100 | 1 | 100 | 1 | 100 | nA max | |
| I_D (ON), On Channel Leakage | 0.04 | | 0.04 | | 0.04 | | nA typ | $V_1 = \pm 10\text{ V}$, $V_2 = \mp 10\text{ V}$; Test Circuit 4 |
| ADG506A | 1 | 200 | 1 | 200 | 1 | 200 | nA max | |
| ADG507A | 1 | 100 | 1 | 100 | 1 | 100 | nA max | |
| I_{DIFF} , Differential Off Output Leakage (ADG507A Only) | | 25 | | 25 | | 25 | nA max | $V_1 = \pm 10\text{ V}$, $V_2 = \mp 10\text{ V}$; Test Circuit 5 |
| DIGITAL CONTROL | | | | | | | | |
| V_{INH} , Input High Voltage | | 2.4 | | 2.4 | | 2.4 | V min | |
| V_{INL} , Input Low Voltage | | 0.8 | | 0.8 | | 0.8 | V max | |
| I_{INL} or I_{INH} | | 1 | | 1 | | 1 | μA max | $V_{IN} = 0$ to V_{DD} |
| C_{IN} Digital Input Capacitance | 8 | | 8 | | 8 | | pF max | |
| DYNAMIC CHARACTERISTICS | | | | | | | | |
| $t_{TRANSITION}^1$ | 200 | | 200 | | 200 | | ns typ | $V_1 = \pm 10\text{ V}$, $V_2 = +10\text{ V}$; Test Circuit 6 |
| | 300 | 400 | 300 | 400 | 300 | 400 | ns max | |
| t_{OPEN}^1 | 50 | | 50 | | 50 | | ns typ | Test Circuit 7 |
| | 25 | 10 | 25 | 10 | 25 | 10 | ns min | |
| t_{ON} (EN) ¹ | 200 | | 200 | | 200 | | ns typ | Test Circuit 8 |
| | 300 | 400 | 300 | 400 | 300 | 400 | ns max | |
| t_{OFF} (EN) ¹ | 200 | | 200 | | 200 | | ns typ | Test Circuit 8 |
| | 300 | 400 | 300 | 400 | 300 | 400 | ns max | |
| OFF Isolation | 68 | | 68 | | 68 | | dB typ | $V_{EN} = 0.8\text{ V}$, $R_L = 1\text{ k}\Omega$, $C_L = 15\text{ pF}$, |
| | 50 | | 50 | | 50 | | dB min | $V_S = 7\text{ V rms}$, $f = 100\text{ kHz}$ |
| C_S (OFF) | 5 | | 5 | | 5 | | pF typ | $V_{EN} = 0.8\text{ V}$ |
| C_D (OFF) | | | | | | | | |
| ADG506A | 44 | | 44 | | 44 | | pF typ | $V_{EN} = 0.8\text{ V}$ |
| ADG507A | 22 | | 22 | | 22 | | pF typ | |
| Q_{INJ} , Charge Injection | 4 | | 4 | | 4 | | pC typ | $R_S = 0\ \Omega$, $V_S = 0\text{ V}$; Test Circuit 9 |
| POWER SUPPLY | | | | | | | | |
| I_{DD} | 0.6 | | 0.6 | | 0.6 | | mA typ | $V_{IN} = V_{INL}$ or V_{INH} |
| | | 1.5 | | 1.5 | | 1.5 | mA max | |
| I_{SS} | 20 | | 20 | | 20 | | μA typ | $V_{IN} = V_{IN}$ or V_{INH} |
| | | 0.2 | | 0.2 | | 0.2 | mA max | |
| Power Dissipation | 10 | | 10 | | 10 | | mW typ | |
| | | 28 | | 28 | | 28 | mW max | |

NOTES

¹Sample tested at +25°C to ensure compliance.

Specifications subject to change without notice.

Single Supply ($V_{DD} = +10.8\text{ V to }+16.5\text{ V}$, $V_{SS} = \text{GND} = 0\text{ V}$ unless otherwise noted)

| Parameter | ADG506A ADG507A K Version | | ADG506A ADG507A B Version | | ADG506A ADG507A T Version | | Units | Comments |
|---|---------------------------------|----------------------|---------------------------------|----------------------|---------------------------------|----------------------|------------------------------|--|
| | +25°C | -40°C to +85°C | +25°C | -40°C to +85°C | +25°C | -55°C to +125°C | | |
| ANALOG SWITCH | | | | | | | | |
| Analog Signal Range | V_{SS} V_{DD} | V_{SS} V_{DD} | V_{SS} V_{DD} | V_{SS} V_{DD} | V_{SS} V_{DD} | V_{SS} V_{DD} | V min V max | |
| R_{ON} | 500 | 1000 | 500 | 1000 | 500 | 1000 | Ω typ Ω max | $0\text{ V} \leq V_S \leq +10\text{ V}$, $I_{DS} = 0.5\text{ mA}$; Test Circuit 1 |
| R_{ON} Drift | 0.6 | | 0.6 | | 0.6 | | %/°C typ | $0\text{ V} \leq V_S \leq +10\text{ V}$, $I_{DS} = 0.5\text{ mA}$ |
| R_{ON} Match | 5 | | 5 | | 5 | | % typ | $0\text{ V} \leq V_S \leq +10\text{ V}$, $I_{DS} = 0.5\text{ mA}$ |
| I_S (OFF), Off Input Leakage | 0.02 1 | 50 | 0.02 1 | 50 | 0.02 1 | 50 | nA typ nA max | $V_1 = +10\text{ V}/0\text{ V}$, $V_2 = 0\text{ V}/+10\text{ V}$; Test Circuit 2 |
| I_D (OFF), Off Output Leakage | 0.04 1 | 200 | 0.04 1 | 200 | 0.04 1 | 200 | nA typ nA max | $V_1 = +10\text{ V}/0\text{ V}$, $V_2 = 0\text{ V}/+10\text{ V}$; Test Circuit 3 |
| ADG507A | 1 | 100 | 1 | 100 | 1 | 100 | nA max | |
| I_D (ON), On Channel Leakage | 0.04 1 | 200 | 0.04 1 | 200 | 0.04 1 | 200 | nA typ nA max | $V_1 = +10\text{ V}/0\text{ V}$, $V_2 = 0\text{ V}/+10\text{ V}$; Test Circuit 4 |
| ADG506A | 1 | 100 | 1 | 100 | 1 | 100 | nA max | |
| ADG507A | 1 | 100 | 1 | 100 | 1 | 100 | nA max | |
| I_{DIFF} , Differential Off Output Leakage (ADG507A Only) | | 25 | | 25 | | 25 | nA max | $V_1 = +10\text{ V}/0\text{ V}$, $V_2 = 0\text{ V}/+10\text{ V}$; Test Circuit 5 |
| DIGITAL CONTROL | | | | | | | | |
| V_{INH} , Input High Voltage | | 2.4 | | 2.4 | | 2.4 | V min | |
| V_{INL} , Input Low Voltage | | 0.8 | | 0.8 | | 0.8 | V max | |
| I_{INL} or I_{INH} | | 1 | | 1 | | 1 | μA max | $V_{IN} = 0$ to V_{DD} |
| C_{IN} , Digital Input Capacitance | 8 | | 8 | | 8 | | pF max | |
| DYNAMIC CHARACTERISTICS | | | | | | | | |
| $t_{TRANSITION}^1$ | 300 | | 300 | | 300 | | ns typ | $V_1 = +10\text{ V}/0\text{ V}$, $V_2 = +10\text{ V}$; Test Circuit 6 |
| | 450 | 600 | 450 | 600 | 450 | 600 | ns max | |
| t_{OPEN}^1 | 50 | | 50 | | 50 | | ns typ | Test Circuit 7 |
| | 25 | 10 | 25 | 10 | 25 | 10 | ns min | |
| t_{ON} (EN) ¹ | 250 | | 250 | | 250 | | ns typ | Test Circuit 8 |
| | 450 | 600 | 450 | 600 | 450 | 600 | ns max | |
| t_{OFF} (EN) ¹ | 250 | | 250 | | 250 | | ns typ | Test Circuit 8 |
| | 450 | 600 | 450 | 600 | 450 | 600 | ns max | |
| OFF Isolation | 68 50 | | 68 50 | | 68 50 | | dB typ dB min | $V_{EN} = 0.8\text{ V}$, $R_L = 1\text{ k}\Omega$, $C_L = 15\text{ pF}$, $V_S = 3.5\text{ V rms}$, $f = 100\text{ kHz}$ |
| C_S (OFF) | 5 | | 5 | | 5 | | pF typ | $V_{EN} = 0.8\text{ V}$ |
| C_D (OFF) | | | | | | | | |
| ADG506A | 44 | | 44 | | 44 | | pF typ | $V_{EN} = 0.8\text{ V}$ |
| ADG507A | 22 | | 22 | | 22 | | pF typ | |
| Q_{INJ} , Charge Injection | 4 | | 4 | | 4 | | pC typ | $R_S = 0\text{ }\Omega$, $V_S = 0\text{ V}$; Test Circuit 9 |
| POWER SUPPLY | | | | | | | | |
| I_{DD} | 0.6 | | 0.6 | | 0.6 | | mA typ | $V_{IN} = V_{INL}$ or V_{INH} |
| | | 1.5 | | 1.5 | | 1.5 | mA max | |
| Power Dissipation | 10 | | 10 | | 10 | | mW typ | |
| | | 25 | | 25 | | 25 | mW max | |

NOTES

¹Sample tested at +25°C to ensure compliance.

Specifications subject to change without notice.

Truth Table (ADG506A)

| A3 | A2 | A1 | A0 | EN | On Switch |
|----|----|----|----|----|-----------|
| X | X | X | X | 0 | NONE |
| 0 | 0 | 0 | 0 | 1 | 1 |
| 0 | 0 | 0 | 1 | 1 | 2 |
| 0 | 0 | 1 | 0 | 1 | 3 |
| 0 | 0 | 1 | 1 | 1 | 4 |
| 0 | 1 | 0 | 0 | 1 | 5 |
| 0 | 1 | 0 | 1 | 1 | 6 |
| 0 | 1 | 1 | 0 | 1 | 7 |
| 0 | 1 | 1 | 1 | 1 | 8 |
| 1 | 0 | 0 | 0 | 1 | 9 |
| 1 | 0 | 0 | 1 | 1 | 10 |
| 1 | 0 | 1 | 0 | 1 | 11 |
| 1 | 0 | 1 | 1 | 1 | 12 |
| 1 | 1 | 0 | 0 | 1 | 13 |
| 1 | 1 | 0 | 1 | 1 | 14 |
| 1 | 1 | 1 | 0 | 1 | 15 |
| 1 | 1 | 1 | 1 | 1 | 16 |

Truth Table (ADG507A)

| A2 | A1 | A0 | EN | On Switch Pair |
|----|----|----|----|----------------|
| X | X | X | 0 | NONE |
| 0 | 0 | 0 | 1 | 1 |
| 0 | 0 | 1 | 1 | 2 |
| 0 | 1 | 0 | 1 | 3 |
| 0 | 1 | 1 | 1 | 4 |
| 1 | 0 | 0 | 1 | 5 |
| 1 | 0 | 1 | 1 | 6 |
| 1 | 1 | 0 | 1 | 7 |
| 1 | 1 | 1 | 1 | 8 |

X = Don't Care

ADG506A/ADG507A

ABSOLUTE MAXIMUM RATINGS¹

(T_A = 25°C unless otherwise noted)

| | |
|--|--|
| V _{DD} to V _{SS} | 44 V |
| V _{DD} to GND | 25 V |
| V _{SS} to GND | -25 V |
| Analog Inputs ² | |
| Voltage at S, D | V _{SS} - 2 V to V _{DD} |
| | + 2 V or |
| | 20 mA, Whichever Occurs First |
| Continuous Current, S or D | 20 mA |
| Pulsed Current S or D | |
| 1 ms Duration, 10% Duty Cycle | 40 mA |
| Digital Inputs ² | |
| Voltage at A, EN | V _{SS} - 4 V |
| | to V _{DD} + 4 V or |
| | 20 mA, Whichever Occurs First |

Power Dissipation (Any Package)

| | |
|------------------------------|---------|
| Up to +75°C | 470 mW |
| Derates above +75°C by | 6 mW/°C |

Operating Temperature

| | |
|---|-----------------|
| Commercial (K Version) | -40°C to +85°C |
| Industrial (B Version) | -40°C to +85°C |
| Extended (T Version) | -55°C to +125°C |
| Storage Temperature Range | -65°C to +150°C |
| Lead Temperature (Soldering, 10 secs) | +300°C |

NOTES

¹Stresses above those listed under Absolute Maximum Ratings may cause permanent damage to the device. This is a stress rating only; functional operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

²Overvoltage at A, EN, S or D will be clamped by diodes. Current should be limited to the Maximum Rating above.

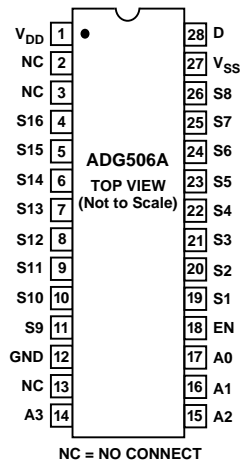
CAUTION

ESD (electrostatic discharge) sensitive device. Electrostatic charges as high as 4000 V readily accumulate on the human body and test equipment and can discharge without detection. Although the ADG506A/ADG507A feature proprietary ESD protection circuitry, permanent damage may occur on devices subjected to high energy electrostatic discharges. Therefore, proper ESD precautions are recommended to avoid performance degradation or loss of functionality.

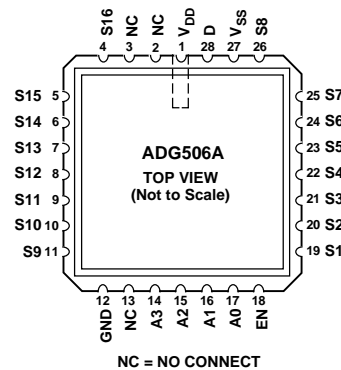


PIN CONFIGURATIONS

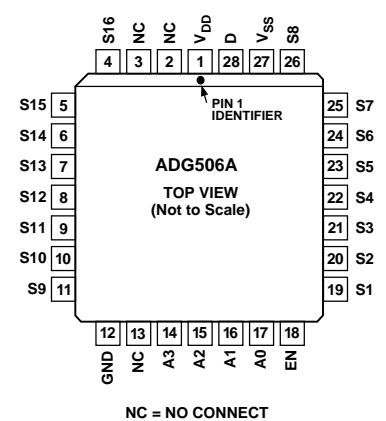
DIP, SOIC



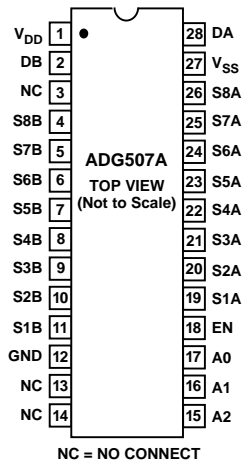
LCCC



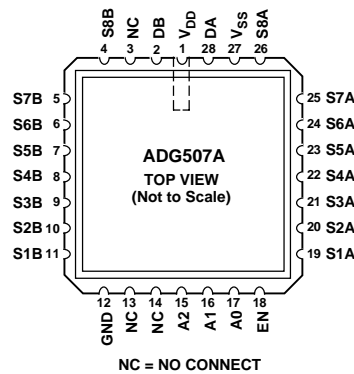
PLCC



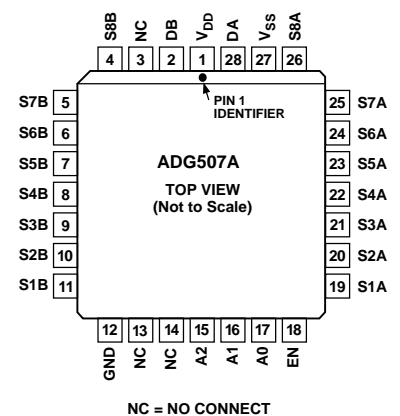
DIP, SOIC, TSSOP



LCCC



PLCC



Typical Performance Characteristics—ADG506A/ADG507A

The multiplexers are guaranteed functional with reduced single or dual supplies down to 4.5 V.



Figure 1. R_{ON} as a Function of V_D (V_S): Dual Supply Voltage, $T_A = +25^\circ\text{C}$

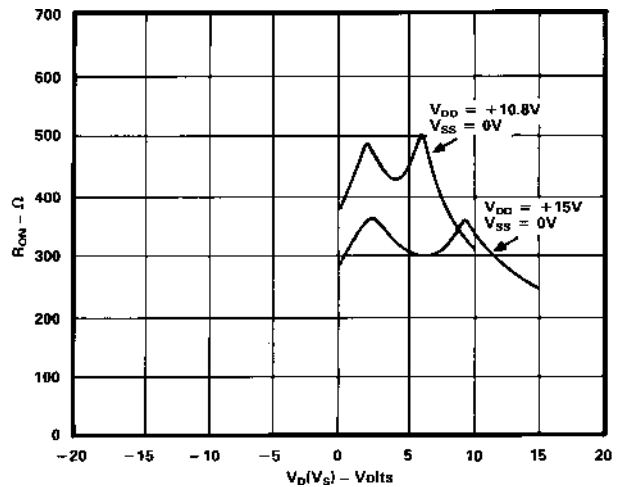


Figure 4. R_{ON} as a Function of V_D (V_S) Single Supply Voltage, $T_A = +25^\circ\text{C}$



Figure 2. Leakage Current as a Function of Temperature (Note: Leakage Currents Reduce as the Supply Voltages Reduce)



Figure 5. Trigger Levels vs. Power Supply Voltage, Dual or Single Supply, $T_A = +25^\circ\text{C}$



Figure 3. $t_{TRANSITION}$ vs. Supply Voltage: Dual and Single Supplies, $T_A = +25^\circ\text{C}$ (Note: For V_{DD} and $V_{SS} < 10\text{ V}$; $V1 = V_{DD}/V_{SS}$, $V2 = V_{SS}/V_{DD}$. See Test Circuit 6)



Figure 6. I_{DD} vs. Supply Voltage: Dual or Single Supply, $T_A = +25^\circ\text{C}$

ADG506A/ADG507A—Test Circuits

Note: All Digital Input Signal Rise and Fall Times Measured from 10% to 90% of 3 V. $t_R = t_F = 20$ ns.



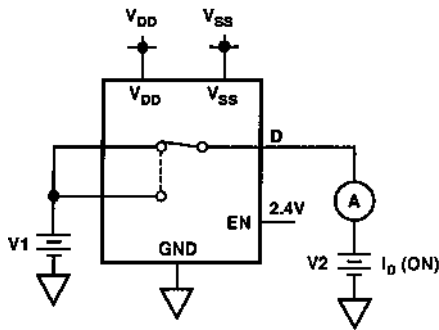
Test Circuit 1. R_{ON}



Test Circuit 2. $I_S(OFF)$



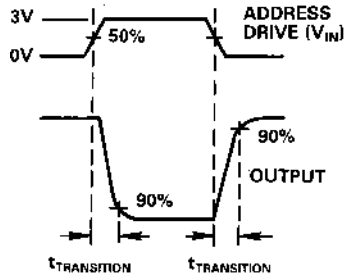
Test Circuit 3. $I_D(OFF)$



Test Circuit 4. $I_D(ON)$

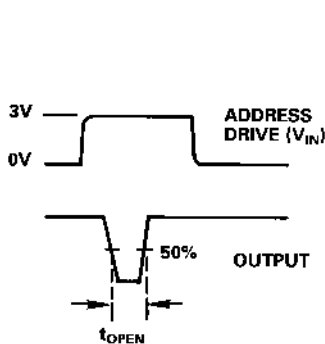
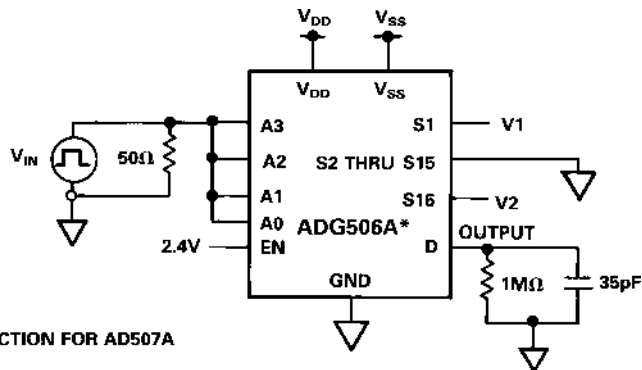


Test Circuit 5. I_{DIFF}



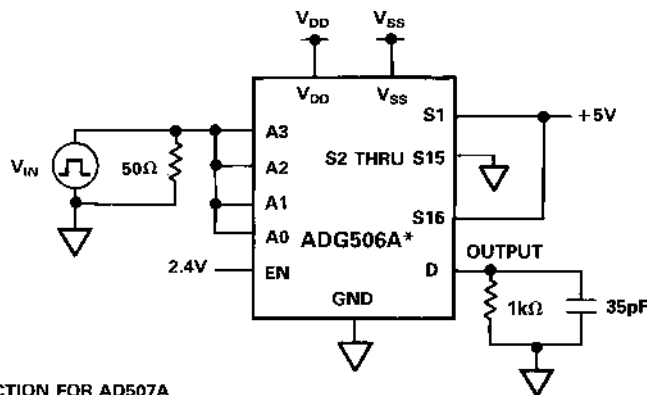
*SIMILAR CONNECTION FOR AD507A

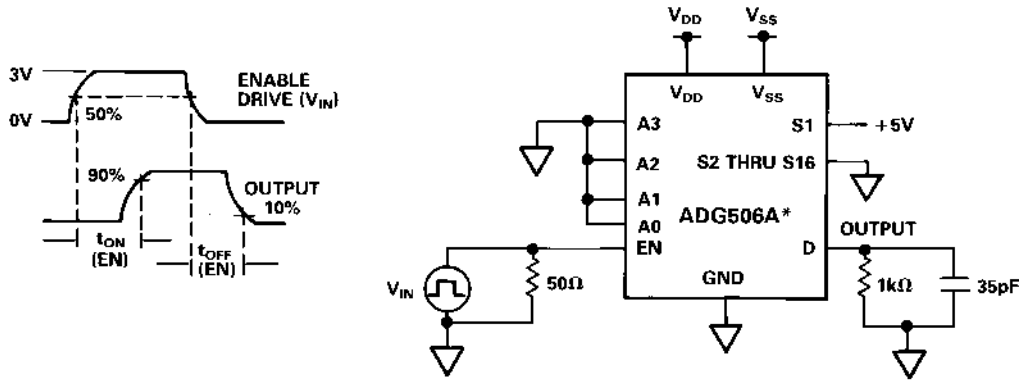
Test Circuit 6. Switching Time of Multiplexer, $t_{TRANSITION}$



*SIMILAR CONNECTION FOR AD507A

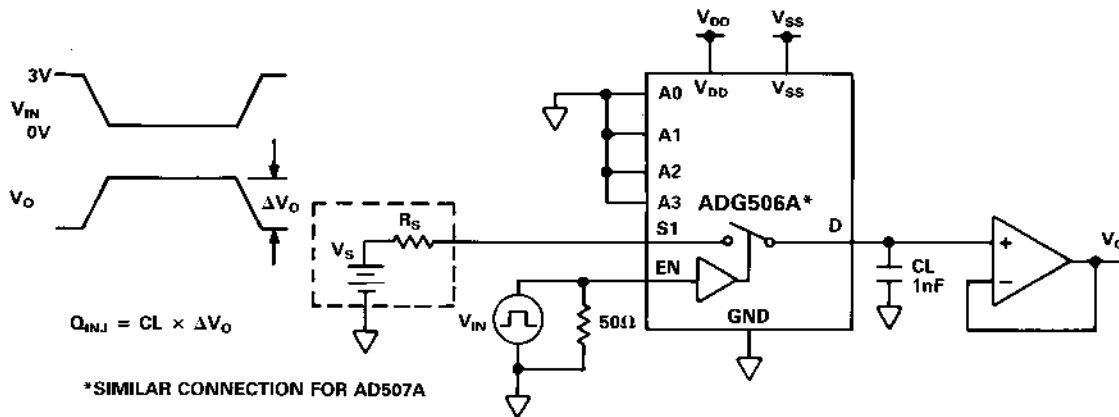
Test Circuit 7. Break-Before-Make Delay, t_{OPEN}





*SIMILAR CONNECTION FOR AD507A

Test Circuit 8. Enable Delay, $t_{ON}(EN)$, $t_{OFF}(EN)$



*SIMILAR CONNECTION FOR AD507A

Test Circuit 9. Charge Injection

SINGLE SUPPLY AUTOMOTIVE APPLICATION

The excellent performance of the multiplexers under single supply conditions makes the ADG506A/ADG507A suitable in applications such as automotive and disc drives where only positive power supply voltages are normally available. The following application circuit shows the ADG507A connected as an 8-channel differential multiplexer in an automotive, data acquisition application circuit.

The AD7580 is a 10-bit successive approximation ADC, which has an on-chip sample-and-hold amplifier and provides a conversion result in 20 μ s. The ADC has differential analog inputs and is configured in the application circuit for a span of 2.5 V over a common-mode range 0 V to +5 V. Wider common-mode ranges can be accommodated. See the AD7579/AD7580 data sheet for more details. The complete system operates from +12 V (+10%) and +5 V supplies. The analog input signals to the ADG507A contain information such as temperature, pressure, speed etc.

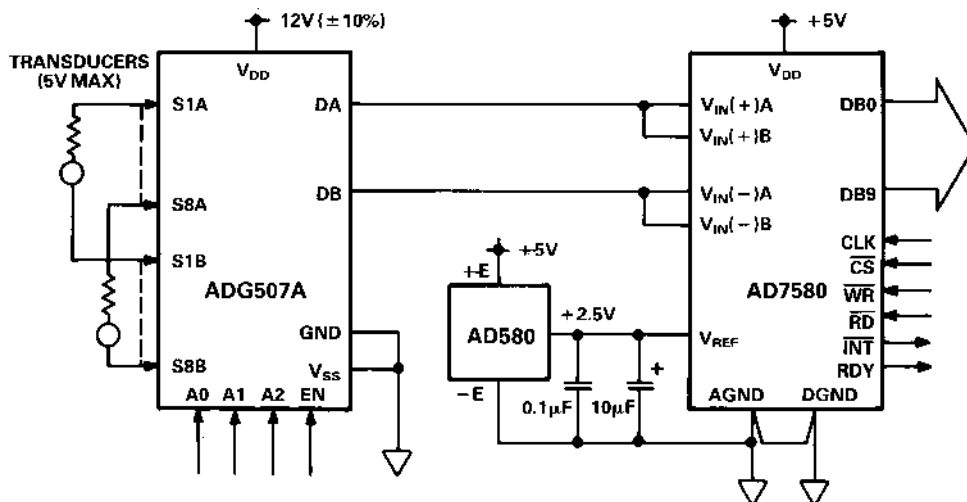


Figure 7. ADG507A in a Single Supply Automotive Data Acquisition Application

ADG506A/ADG507A

TERMINOLOGY

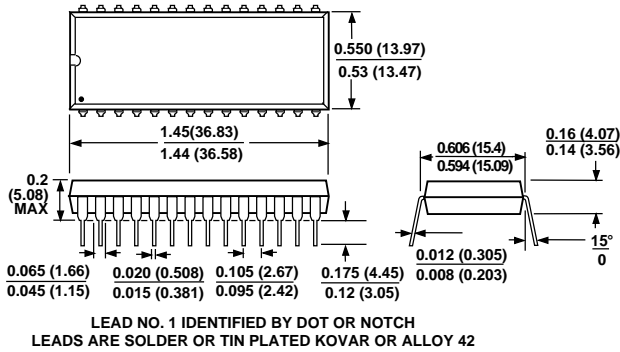
| | |
|-----------------|--|
| R_{ON} | Ohmic resistance between terminals D and S |
| R_{ON} Match | Difference between the R_{ON} of any two channels |
| R_{ON} Drift | Change in R_{ON} versus temperature |
| I_S (OFF) | Source terminal leakage current when the switch is off |
| I_D (OFF) | Drain terminal leakage current when the switch is off |
| I_D (ON) | Leakage current that flows from the closed switch into the body |
| V_S (V_D) | Analog voltage on terminal S or D |
| C_S (OFF) | Channel input capacitance for "OFF" condition |
| C_D (OFF) | Channel output capacitance for "OFF" condition |
| C_{IN} | Digital input capacitance |
| t_{ON} (EN) | Delay time between the 50% and 90% points of the digital input and switch "ON" condition |

| | |
|-------------------------|--|
| t_{OFF} (EN) | Delay time between the 50% and 10% points of the digital input and switch "OFF" condition |
| $t_{TRANSITION}$ | Delay time between the 50% and 90% points of the digital inputs and switch "ON" condition when switching from one address state to another |
| t_{OPEN} | "OFF" time measured between 50% points of both switches when switching from one address state to another |
| V_{INL} | Maximum input voltage for Logic "0" |
| V_{INH} | Minimum input voltage for Logic "1" |
| I_{INL} (I_{INH}) | Input current of the digital input |
| V_{DD} | Most positive voltage supply |
| V_{SS} | Most negative voltage supply |
| I_{DD} | Positive supply current |
| I_{SS} | Negative supply current |

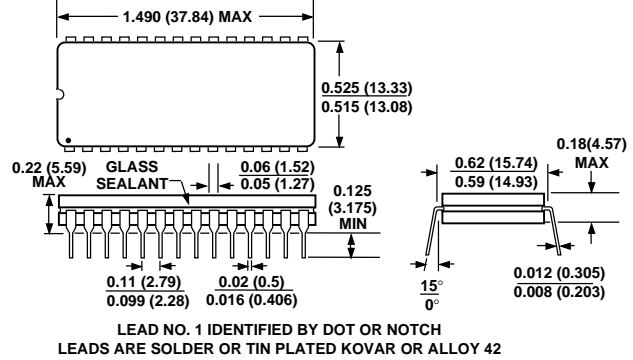
OUTLINE DIMENSIONS

Dimensions shown in inches and (mm).

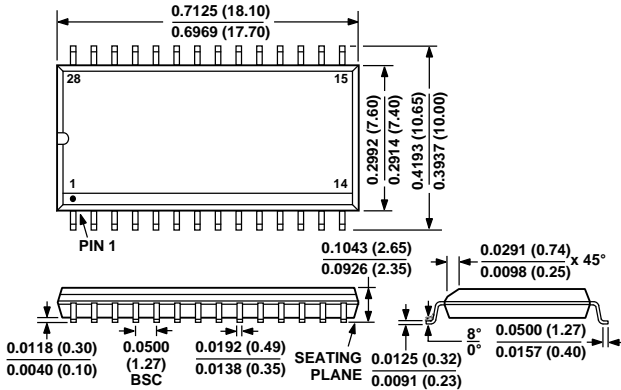
28-Lead Plastic DIP (Suffix N)



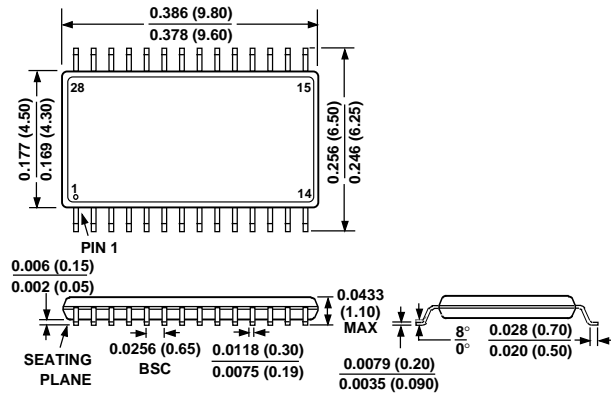
28-Lead Cerdip (Suffix Q)



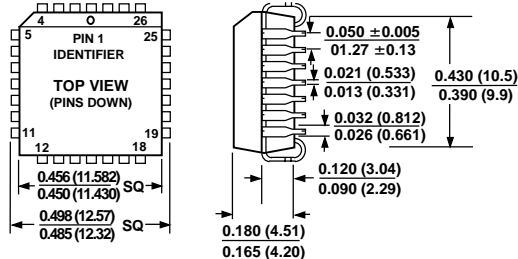
28-Lead SOIC (Suffix R)



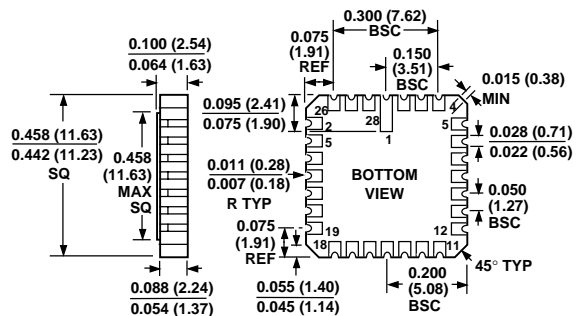
28-Lead TSSOP (Suffix RU)



28-Terminal Plastic Leaded Chip Carrier (Suffix P)



28-Terminal Leadless Ceramic Chip Carrier (Suffix E)



Данный компонент на территории Российской Федерации

Вы можете приобрести в компании MosChip.

Для оперативного оформления запроса Вам необходимо перейти по данной ссылке:

<http://moschip.ru/get-element>

Вы можете разместить у нас заказ для любого Вашего проекта, будь то серийное производство или разработка единичного прибора.

В нашем ассортименте представлены ведущие мировые производители активных и пассивных электронных компонентов.

Нашей специализацией является поставка электронной компонентной базы двойного назначения, продукции таких производителей как XILINX, Intel (ex.ALTERA), Vicor, Microchip, Texas Instruments, Analog Devices, Mini-Circuits, Amphenol, Glenair.

Сотрудничество с глобальными дистрибьюторами электронных компонентов, предоставляет возможность заказывать и получать с международных складов практически любой перечень компонентов в оптимальные для Вас сроки.

На всех этапах разработки и производства наши партнеры могут получить квалифицированную поддержку опытных инженеров.

Система менеджмента качества компании отвечает требованиям в соответствии с ГОСТ Р ИСО 9001, ГОСТ РВ 0015-002 и ЭС РД 009

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